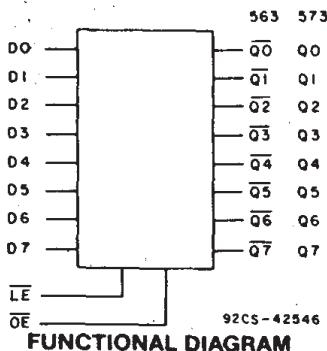


CD54/74AC563, CD54/74AC573

CD54/74ACT563, CD54/74ACT573



Data sheet acquired from Harris Semiconductor
SCHS291



Octal Transparent Latch, 3-State

CD54/74AC/ACT563 - Inverting

CD54/74AC/ACT573 - Non-Inverting

Type Features:

- Buffered inputs
- Typical propagation delay:
4.3 ns @ $V_{cc} = 5$ V, $T_A = 25^\circ C$, $C_L = 50 \mu F$

The RCA-CD54/74AC563 and CD54/74AC573 and the CD54/74ACT563 and CD54/74ACT573 octal transparent 3-state latches use the RCA ADVANCED CMOS technology. The outputs are transparent to the inputs when the Latch Enable (\overline{LE}) is HIGH. When the Latch Enable (\overline{LE}) goes LOW, the data is latched. The Output Enable (\overline{OE}) controls the 3-state outputs. When the Output Enable (\overline{OE}) is HIGH, the outputs are in the high-impedance state. The latch operation is independent of the state of the Output Enable.

The CD74AC/ACT563 and CD74AC/ACT573 are supplied in 20-lead dual-in-line plastic packages (E suffix) and in 20-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over the following temperature ranges: Commercial (0 to $70^\circ C$); Industrial (-40 to +85°C); and Extended Industrial/Military (-55 to +125°C).

The CD54AC/ACT563 and CD54AC/ACT573, available in chip form (H suffix), are operable over the -55 to +125°C temperature range.

Family Features:

- Exceeds 2-kV ESD Protection - MIL-STD-883, Method 3015
- SCR-Latchup-resistant CMOS process and circuit design
- Speed of bipolar FAST*/AS/S with significantly reduced power consumption
- Balanced propagation delays
- AC types feature 1.5-V to 5.5-V operation and balanced noise immunity at 30% of the supply
- $\pm 24\text{-mA}$ output drive current
 - Fanout to 15 FAST* ICs
 - Drives 50-ohm transmission lines

*FAST is a Registered Trademark of Fairchild Semiconductor Corp.

TRUTH TABLE

Output Enable	Latch Enable	Data	AC/ACT563 Output	AC/ACT573 Output
L	H	H	L	H
L	H	L	H	L
L	L	I	H	L
L	L	h	L	H
H	X	X	Z	Z

Note:

L = Low voltage level

H = High voltage level

I = Low voltage level one set-up time prior to the high to low latch enable transition

h = High voltage level one set-up time prior to the high to low latch enable transition

X = Don't Care

Z = High Impedance State

This data sheet is applicable to the CD74AC563, CD54/74AC573, and CD54/74ACT573. The CD54AC563 and CD54/74ACT563 were not acquired from Harris Semiconductor.

File Number 1956

CD54/74AC563, CD54/74AC573 CD54/74ACT563, CD54/74ACT573

MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE (V _{cc})	-0.5 to 6 V
DC INPUT DIODE CURRENT, I _{IN} (for V _i < -0.5 V or V _i > V _{cc} + 0.5 V)	±20 mA
DC OUTPUT DIODE CURRENT, I _{OUT} (for V _o < -0.5 V or V _o > V _{cc} + 0.5 V)	±50 mA
DC OUTPUT SOURCE OR SINK CURRENT per Output Pin, I _O (for V _o > -0.5 V or V _o < V _{cc} + 0.5 V)	±50 mA
DC V _{cc} or GROUND CURRENT (I _{cc} or I _{GND})	±100 mA*

POWER DISSIPATION PER PACKAGE (P_D):

For T _A = -55 to +100°C (PACKAGE TYPE E)	500 mW
For T _A = +100 to +125°C (PACKAGE TYPE E)	Derate Linearly at 8 mW/°C to 300 mW
For T _A = -55 to +70°C (PACKAGE TYPE M)	400 mW
For T _A = +70 to +125°C (PACKAGE TYPE M)	Derate Linearly at 6 mW/°C to 70 mW

OPERATING-TEMPERATURE RANGE (T_A):

PACKAGE TYPE F	-55 to +125°C
PACKAGE TYPE E, M	-40 to +125°C
STORAGE TEMPERATURE (T _{SG})	-65 to +150°C

LEAD TEMPERATURE (DURING SOLDERING):

At distance 1/16 ± 1/32 in. (1.59 ± 0.79 mm) from case for 10 s maximum	+265°C
Unit inserted into PC board min. thickness 1/16 in. (1.59 mm) with solder contacting lead tips only	+300°C

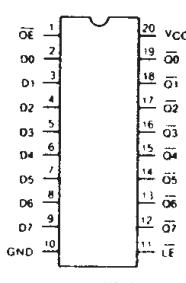
*For up to 4 outputs per device; add ± 25 mA for each additional output.

RECOMMENDED OPERATING CONDITIONS:

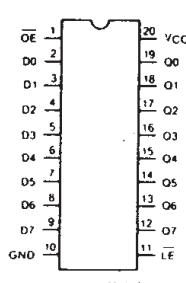
For maximum reliability, normal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIMITS		UNITS
	MIN.	MAX.	
Supply-Voltage Range, V _{cc} *: (For T _A = Full Package-Temperature Range)			
AC Types	1.5	5.5	V
ACT Types	4.5	5.5	V
DC Input or Output Voltage, V _i , V _o	0	V _{cc}	V
Operating Temperature, T _A :	-55	+125	°C
Input Rise and Fall Slew Rate, dt/dv			
at 1.5 V to 3 V(AC Types)	0	50	ns/V
at 3.6 V to 5.5 V(AC Types)	0	20	ns/V
at 4.5 V to 5.5 V(AC Types)	0	10	ns/V

*Unless otherwise specified, all voltages are referenced to ground.

TERMINAL ASSIGNMENT DIAGRAMS

CD54/74AC563, CD54/74ACT563



CD54/74AC573, CD54/74ACT573

Technical Data

**CD54/74AC563, CD54/74AC573
CD54/74ACT563, CD54/74ACT573**

STATIC ELECTRICAL CHARACTERISTICS: AC Series

CHARACTERISTICS	TEST CONDITIONS		V _{cc} (V)	AMBIENT TEMPERATURE (T _A) - °C						UNITS	
				+25		-40 to +85		-55 to +125			
	V _i (V)	I _o (mA)		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
High-Level Input Voltage	V _{ih}			1.5	1.2	—	1.2	—	1.2	V	
				3	2.1	—	2.1	—	2.1		
				5.5	3.85	—	3.85	—	3.85		
Low-Level Input Voltage	V _{il}			1.5	—	0.3	—	0.3	—	V	
				3	—	0.9	—	0.9	—		
				5.5	—	1.65	—	1.65	—		
High-Level Output Voltage	V _{oh}	V _{ih}	-0.05	1.5	1.4	—	1.4	—	1.4	V	
			-0.05	3	2.9	—	2.9	—	2.9		
			-0.05	4.5	4.4	—	4.4	—	4.4		
		V _{il}	-4	3	2.58	—	2.48	—	2.4		
			-24	4.5	3.94	—	3.8	—	3.7		
			#,*	75	5.5	—	3.85	—	—		
			-50	5.5	—	—	—	—	3.85		
Low-Level Output Voltage	V _{ol}	V _{ih}	0.05	1.5	—	0.1	—	0.1	—	V	
			0.05	3	—	0.1	—	0.1	—		
			0.05	4.5	—	0.1	—	0.1	—		
		V _{il}	12	3	—	0.36	—	0.44	—		
			24	4.5	—	0.36	—	0.44	—		
			#,*	75	5.5	—	—	1.65	—		
			50	5.5	—	—	—	—	1.65		
Input Leakage Current	I _i	V _{cc} or GND		5.5	—	±0.1	—	±1	—	±1	μA
3-State Leakage Current	I _{oz}	V _{ih} or V _{il} V _o = V _{cc} or GND		5.5	—	±0.5	—	±5	—	±10	μA
Quiescent Supply Current, MSI	I _{cc}	V _{cc} or GND	0	5.5	—	8	—	80	—	160	μA

#Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

*Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

**CD54/74AC563, CD54/74AC573
CD54/74ACT563, CD54/74ACT573**

STATIC ELECTRICAL CHARACTERISTICS: ACT Series

CHARACTERISTICS	TEST CONDITIONS		V _{cc} (V)	AMBIENT TEMPERATURE (T _A) - °C						UNITS	
				+25		-40 to +85		-55 to +125			
	V _{iH}	I _o (mA)		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
High-Level Input Voltage	V _{iH}		4.5 to 5.5	2	—	2	—	2	—	V	
Low-Level Input Voltage	V _{iL}		4.5 to 5.5	—	0.8	—	0.8	—	0.8	V	
High-Level Output Voltage	V _{oH}	V _{iH} or V _{iL} #, *	-0.05 -24 -75 -50	4.5 4.5 5.5 5.5	4.4 3.94 — —	— 3.8 3.85 —	— — — —	4.4 3.7 — 3.85	— — — —	V	
Low-Level Output Voltage	V _{oL}	V _{iH} or V _{iL} #, *	0.05 24 75 50	4.5 4.5 5.5 5.5	— — — —	0.1 0.36 — —	— 0.44 1.65 —	— — — —	0.1 0.5 — 1.65	V	
Input Leakage Current	I _i	V _{cc} or GND		5.5	—	±0.1	—	±1	—	±1	μA
3-State Leakage Current	I _{oZ}	V _{iH} or V _{iL} V _o = V _{cc} or GND		5.5	—	±0.5	—	±5	—	±10	μA
Quiescent Supply Current, MSI	I _{cc}	V _{cc} or GND	0	5.5	—	8	—	80	—	160	μA
Additional Quiescent Supply Current per Input Pin TTL Inputs High 1 Unit Load	ΔI _{cc}	V _{cc} -2.1		4.5 to 5.5	—	2.4	—	2.8	—	3	mA

#Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

*Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

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ACT INPUT LOADING TABLE

INPUT	UNIT LOAD*	
	ACT563	ACT573
OE	0.87	0.87
Dn	0.5	0.5
LE	0.8	0.8

*Unit load is ΔI_{cc} limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25°C.

Technical Data

**CD54/74AC563, CD54/74AC573
CD54/74ACT563, CD54/74ACT573**

PREREQUISITE FOR SWITCHING: AC Series

CHARACTERISTICS	SYMBOL	V _{CC} (V)	AMBIENT TEMPERATURE (T _A) - °C				UNITS	
			-40 to +85		-55 to +125			
			MIN.	MAX.	MIN.	MAX.		
LE Pulse Width	t _W	1.5 3.3* 5†	44 4.9 3.5	— — —	50 5.6 4	— — —	ns	
Setup Time Data to LE	t _{SU}	1.5 3.3 5	2 2 2	— — —	2 2 2	— — —	ns	
Hold Time Data to LE	t _H	1.5 3.3 5	33 3.7 2.6	— — —	38 4.2 3	— — —	ns	

*3.3 V: min. is @ 3 V

†5 V: min. is @ 4.5 V

SWITCHING CHARACTERISTICS: AC Series; t_W, t_H = 3 ns, C_L = 50 pF

CHARACTERISTICS	SYMBOL	V _{CC} (V)	AMBIENT TEMPERATURE (T _A) - °C				UNITS		
			-40 to +85		-55 to +125				
			MIN.	MAX.	MIN.	MAX.			
Propagation Delays: Data to Qn AC563	t _{PLH} t _{PHL}	1.5 3.3* 5†	— 3.8 2.7	119 13.4 9.5	— 3.7 2.6	131 14.7 10.5	ns		
AC573	t _{PLH} t _{PHL}	1.5 3.3 5	— 3.1 2.2	96 10.8 7.7	— 3 2.1	106 11.9 8.5	ns		
LE on Qn AC563	t _{PLH} t _{PHL}	1.5 3.3 5	— 4.3 3.1	136 15.3 10.9	— 4.2 3	150 16.8 12	ns		
AC573	t _{PLH} t _{PHL}	1.5 3.3 5	— 4.3 3.1	136 15.3 10.9	— 4.2 3	150 16.8 12	ns		
Output Enable Times	t _{PZL} t _{PZH}	1.5 3.3 5	— 4.1 2.7	119 14.4 9.5	— 4 2.6	131 15.8 10.5	ns		
Output Disable Times	t _{PLZ} t _{PHZ}	1.5 3.3 5	— 3.7 3	131 13.1 10.5	— 3.6 2.9	144 14.4 11.5	ns		
Power Dissipation Capacitance	C _{PD} \$	—	63 Typ.		63 Typ.		pF		
Min. (Valley) V _{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V _{OHV} See Fig. 1	5	4 Typ. @ 25°C				V		
Max. (Peak) V _{OL} During Switching of Other Outputs (Output Under Test Not Switching)	V _{OLP} See Fig. 1	5	1 Typ. @ 25°C				V		
Input Capacitance	C _I	—	—	10	—	10	pF		
3-State Output Capacitance	C _O	—	—	15	—	15	pF		

*3.3 V: min. is @ 3.6 V
max. is @ 3 V

†5 V: min. is @ 5.5 V
max. is @ 4.5 V

§C_{PD} is used to determine the dynamic power consumption, per latch.

$$P_0 = V_{CC}^2 f_i (C_{PD} + C_L) \text{ where } f_i = \text{input frequency}$$

C_L = output load capacitance

V_{CC} = supply voltage.

**CD54/74AC563, CD54/74AC573
CD54/74ACT563, CD54/74ACT573**

PREREQUISITE FOR SWITCHING: ACT Series

CHARACTERISTICS	SYMBOL	V_{CC} (V)	AMBIENT TEMPERATURE (T_A) - °C				UNITS	
			-40 to +85		-55 to +125			
			MIN.	MAX.	MIN.	MAX.		
LE Pulse Width	t_W	5†	3.5	—	4	—	ns	
Setup Time Data to LE	t_{SU}	5	2	—	2	—	ns	
Hold Time Data to LE	t_H	5	2.6	—	3	—	ns	

†5 V: min. is @ 4.5 V

SWITCHING CHARACTERISTICS: ACT Series; $t_r, t_f = 3$ ns, $C_L = 50$ pF

CHARACTERISTICS	SYMBOL	V_{CC} (V)	AMBIENT TEMPERATURE (T_A) - °C				UNITS		
			-40 to +85		-55 to +125				
			MIN.	MAX.	MIN.	MAX.			
Propagation Delays: Data to Qn 563	t_{PLH} t_{PHL}	5†	2.9	10.4	2.9	11.4	ns		
573			2.7	9.4	2.6	10.4			
LE to Qn 563 573	t_{PLH} t_{PHL}	5	3.2	11.4	3.1	12.5	ns		
Output Enable Times	t_{PZL} t_{PZH}	5	3.5	12.3	3.4	13.5	ns		
Output Disable Times	t_{PLZ} t_{PHZ}	5	3.2	11.4	3.1	12.5	ns		
Power Dissipation Capacitance	$C_{PD\$}$	—	63 Typ.		63 Typ.		pF		
Min. (Valley) V_{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V_{OHV} See Fig. 1	5	4 Typ. @ 25°C				V		
Max. (Peak) V_{OL} During Switching of Other Outputs (Output Under Test Not Switching)	V_{OLP} See Fig. 1	5	1 Typ. @ 25°C				V		
Input Capacitance	C_I	—	—	10	—	10	pF		
3-State Output Capacitance	C_O	—	—	15	—	15	pF		

†5 V: min. is @ 5.5 V
max. is @ 4.5 V

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§ C_{PD} is used to determine the dynamic power consumption, per latch.

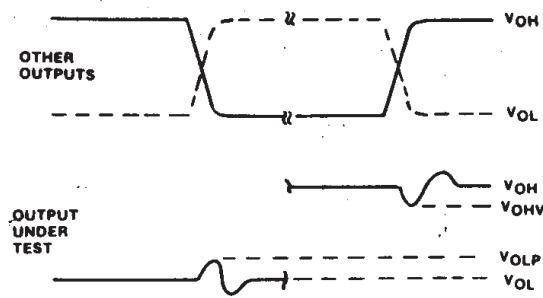
$$P_D = V_{CC}^2 f_i (C_{PD} + C_L) + V_{CC} \Delta I_{CC} \text{ where } f_i = \text{input frequency}$$

 C_L = output load capacitance V_{CC} = supply voltage.

Technical Data

CD54/74AC563, CD54/74AC573 CD54/74ACT563, CD54/74ACT573

PARAMETER MEASUREMENT INFORMATION

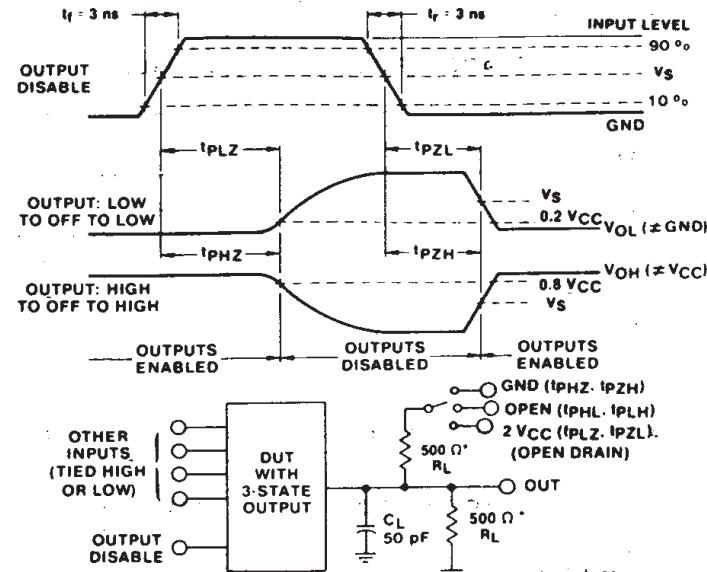


NOTES:

1. V_{OH} AND V_{OLP} ARE MEASURED WITH RESPECT TO A GROUND REFERENCE NEAR THE OUTPUT UNDER TEST.
2. INPUT PULSES HAVE THE FOLLOWING CHARACTERISTICS:
PRR = 1 MHz, t_r = 3 ns, t_f = 3 ns, SKEW 1 ns.
3. R.F. FIXTURE WITH 700-MHz DESIGN RULES REQUIRED.
IC SHOULD BE SOLDERED INTO TEST BOARD AND BYPASSED WITH 0.1 μ F CAPACITOR. SCOPE AND PROBES REQUIRE 700-MHz BANDWIDTH.

92CS-4240E

Fig. 1 - Simultaneous switching transient waveforms.



*FOR AC SERIES ONLY: WHEN V_{CC} = 1.5 V, R_L = 1 k Ω

Fig. 2 - Three-state propagation delay waveforms and test circuit.

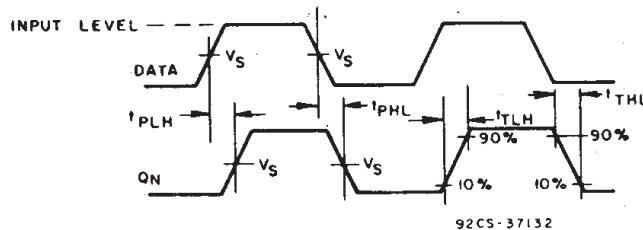


Fig. 3 - Data to Q_n output propagation delays.

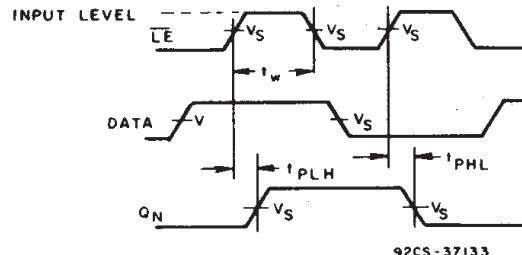


Fig. 4 - Latch enable propagation delays.

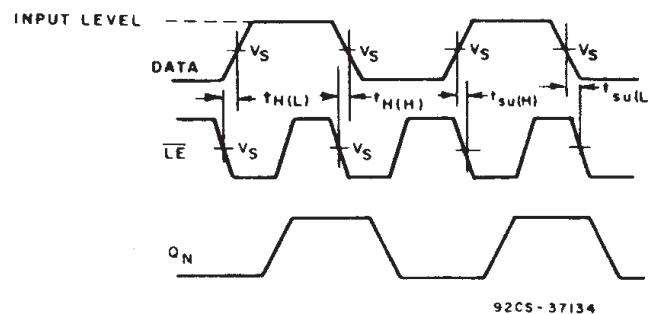
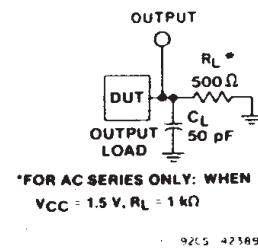


Fig. 5 - Latch enable prerequisite times.



*FOR AC SERIES ONLY: WHEN
V_{CC} = 1.5 V, R_L = 1 k Ω

Fig. 6 - Test circuit.

	CD54/74AC	CD54/74ACT
Input Level	V _{CC}	3 V
Input Switching Voltage, V _S	0.5 V _{CC}	1.5 V
Output Switching Voltage, V _S	0.5 V _{CC}	0.5 V _{CC}

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